TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7WH74FU, TC7WH74FK

D-TYPE FLIP FLOP WITH PRESET AND CLEAR

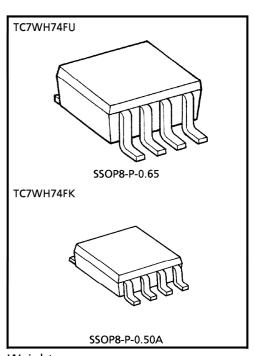
The TC7WH74 is an advanced high speed CMOS D-FLIP FLOP fabricated with silicon gate CMOS technology. It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

The signal level applied to the D INPUT is transferred to Q OUTPUT during the positive going transition of the CK pulse.

CLR and PR are independent of the CK and are accomplished by setting the appropriate input low. An input protection circuit ensures that 0 to 7V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5V to 3V system and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

FEATURES

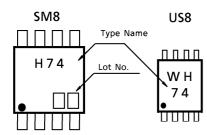
- High Speed \cdots $f_{MAX} = 170 \text{MHz}$ (Typ.) at $V_{CC} = 5 \text{V}$ Low Power Dissipation \cdots $I_{CC} = 2 \mu A$ (Max.) at $Ta = 25 ^{\circ}\text{C}$ High Noise Immunity \cdots $V_{NIH} = V_{NIL} = 28 \%$ V_{CC}
- Power Down Protection is provided on all inputs.
- Balanced Propagation Delays ······ t_{pLH} ≒t_{pHL}
- Wide Operation Voltage Range ··· V_{CC} (opr) = 2~5.5V



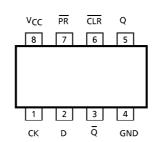
Weight

SSOP8-P-0.65 : 0.02g (Typ.) SSOP8-P-0.50A : 0.01g (Typ.)

MARKING



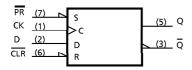
PIN ASSIGNMENT (TOP VIEW)



MAXIMUM RATINGS (Ta = 25° C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage Range	VCC	-0.5~7.0	V	
DC Input Voltage	VIN	-0.5~7.0	V	
DC Output Voltage	Vout	-0.5~V _{CC} +0.5	V	
Input Diode Current	ΙΙΚ	- 20	mA	
Output Diode Current	loк	± 20	mA	
DC Output Current	lout	± 25	mA	
DC V _{CC} /Ground Current	lcc	± 50	mA	
Dawar Dissination	D-	300 (SM8)	m2\A/	
Power Dissipation	PD	200 (US8)	mW	
Storage Temperature	T _{stg}	- 65~150	°C	
Lead Temperature (10 s)	TL	260	°C	

LOGIC DIAGRAM



TRUTH TABLE

	INP	JTS		OUTPUTS		FUNCTION
CLR	PR	D	CK	Q	Q	FUNCTION
L	Н	×	×	L	Н	CLEAR
Н	L	×	×	Н	L	PRESET
L	L	×	×	Н	Н	_
Н	Н	L	<u>_</u>	L	Н	_
Н	Н	Н		Н	L	_
Н	Н	×	T_	Qn	\overline{Q}_n	NO CHANGE

x : Don't care

RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage	V _{CC}	2~5.5	V	
Input Voltage	V _{IN}	0~V _{CC}	٧	
Output Voltage	Vout	0~V _{CC}	٧	
Operating Temperature	T _{opr}	- 40∼8 5	Ĵ	
Input Rise and Fall Time	dt/dv	$0 \sim 100 \text{ (V}_{CC} = 3.3 \pm 0.3 \text{V)}$	ns/V	
Input Rise and Fall Time	at/dv	$0\sim20 \ (V_{CC} = 5 \pm 0.5V)$	115/V	

DC ELECTRICAL CHARACTERISTICS

CHADACTEDISTIC	ARACTERISTIC SYMBOL TEST CONDITION		ONDITION	Vcc	٦	Ta = 25°C		Ta = −40~85°C		UNIT
CHARACTERISTIC			Vcc (V)	MIN.	TYP.	MAX.	MIN.	MAX.	OIVII	
High-Level	Lovel			2.0	1.5		_	1.5	_	
Input Voltage	V _{IH}		_		V _{CC} ×0.7	1	_	V _{CC} ×0.7		V
Low-Level				2.0	_	_	0.5	_	0.5	
Input Voltage	VIL		_		_	_	V _C C × 0.3	_	V _C C ×0.3	V
			I _{OH} = -50μA	2.0	1.9	2.0	_	1.9	_	V
lliah Laval	V _{ОН}	V _{IN} = V _{IH} or V _{IL}		3.0	2.9	3.0	_	2.9	_	
High-Level Output Voltage				4.5	4.4	4.5	_	4.4	_	
Output Voltage			$I_{OH} = -4mA$	3.0	2.58	_	_	2.48	_	
			$I_{OH} = -8mA$	4.5	3.94	_	_	3.80	_	
			I _{OL} = 50μA	2.0	_	0.0	0.1	_	0.1	V
Low-Level		OL V _{IN} = V _{IH} or V _{IL}		3.0	_	0.0	0.1	_	0.1	
Output Voltage	VOL			4.5	_	0.0	0.1	_	0.1	
Output Voltage		0, 41	$I_{OL} = 4mA$	3.0			0.36		0.44	
			I _{OL} = 8mA	4.5	_	_	0.36	_	0.44	
Input Leakage Current	IN	V _{IN} = V _{CC} or GND		0~ 5.5		_	± 0.1	_	± 1.0	μΑ
Quiescent Supply Current	lcc	V _{IN} = V _{CC} o	V _{IN} = V _{CC} or GND		_	_	2.0	_	20.0	μΑ

TIMING REQUIREMENTS (Input $t_r = t_f = 3ns$)

CHARACTERISTIC	SYMBOL TEST CONDITION			Ta = 25°C		Ta = -40~85°C	UNIT
CHARACTERISTIC	STIVIBUL	TEST CONDITION	V _{CC} (V)	TYP.	LIMIT	LIMIT	UNIT
Minimum Pulse	t _W (L)		3.3 ± 0.3	_	6.0	7.0	ne
Width (CLOCK)	t _W (H)		5.0 ± 0.5	_	5.0	5.0	ns
Minimum Pulse	+,,,(1)		3.3 ± 0.3	1	6.0	7.0	ne
Width (CLR, PR)	t _W (L)		5.0 ± 0.5	-	5.0	5.0	ns
Minimum Set-up	4		3.3 ± 0.3	-	7.0	7.0	ns
Time	t _s		5.0 ± 0.5		5.0	5.0	115
Minimum Hold	+1		3.3 ± 0.3		0.5	0.5	ns
Time	th		5.0 ± 0.5	1	0.5	0.5	115
Minimum Removal	+		3.3 ± 0.3	_	5.0	5.0	ns
Time (CLR, PR)	^t rem		5.0 ± 0.5	1	3.0	3.0	115

AC ELECTRICAL CHARACTERISTICS (Inpu	$ut t_r = t_f$	=3ns)
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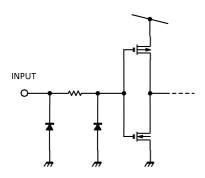
CHARACTERISTIC	SYMBOL TEST		CONDITION		Ta = 25°C			Ta = -4	UNIT	
CHARACTERISTIC S	STIVIBUL	•	V _{CC} (V)	C _L (pF)	MIN.	TYP.	MAX.	MIN.	MAX.	
D 11 D1	opagation Delay		3.3 ± 0.3	15	_	6.7	11.9	1.0	14.0	
Time			3.3 ± 0.3	50	_	9.2	15.4	1.0	17.5	
(CK-Q, \overline{Q})	tpHL		5.0 ± 0.5	15	_	4.6	7.3	1.0	8.5	ns
(CK-Q, Q)			3.0 ± 0.3	50	_	6.1	9.3	1.0	10.5	
			3.3 ± 0.3	15	_	7.6	12.3	1.0	14.5	
Propagation Delay Time	tpLH	3.3 ± 0.3	50	_	10.1	15.8	1.0	18.0]	
$(\overline{CLR}, \overline{PR}-Q, \overline{Q})$	tpHL	5.0 ± 0.	50+05	15	_	4.8	7.7	1.0	9.0	ns ns
(CLN, FN-Q, Q)			3.0 ± 0.3	50	_	6.3	9.7	1.0	11.0	
	ximum Clock	3.3 ± 0.3 5.0 ± 0.5	33+03	15	80	125	_	70	_	
Maximum Clock			50	50	75	_	45	_	MHz	
Frequency	fMAX		15	130	170	_	110	_	IVITZ	
			50	90	115	_	75	_		
Input Capacitance	CIN				_	4	10	_	10	рF
Power Dissipation	CDD	(Note 1)		·		22				рF
Capacitance	C _{PD}					~~				Pi

(Note 1): CpD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

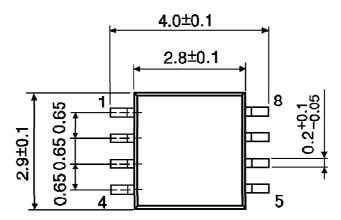
$$I_{CC \text{ (opr)}} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

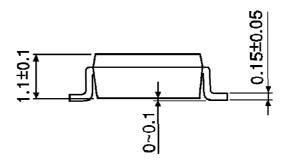
INPUT EQUIVALENT CIRCUIT



PACKAGE DIMENSIONS

SSOP8-P-0.65 Unit: mm

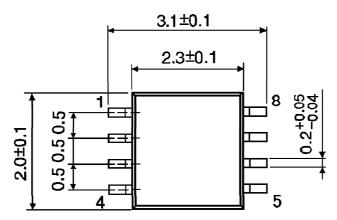


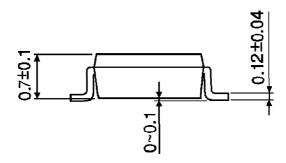


Weight: 0.02g (Typ.)

PACKAGE DIMENSIONS

SSOP8-P-0.50A Unit: mm





Weight: 0.01g (Typ.)

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